

XF1 set

Near-Field Probes 30 MHz up to 6 GHz

LANGER
EMV-Technik



Short description

The XF1 set consists of four magnetic field probes and one E-field probe for measuring E-fields and magnetic fields from 30 MHz to 6 GHz on electronic assemblies during the development stage. Due to their integrated impedance matching, the probes are less sensitive in the lower frequency range than the RF-type probes. The probe heads of the XF1 set allow for the step by step localization of magnetic-field interference sources on assemblies. First the XF-R 400-1 probe is used to detect electromagnetic interference from greater distances. Next, the higher resolution probes can be used to more precisely detect the interference sources. The E-field probe is used for the detection of electric interference fields near the assemblies. With trained use of the near-field probes, field orientation and field distribution can be detected. The near-field probes are small and handy. They have a current attenuating sheath and, therefore, are electrically shielded. They can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. They have an internal terminating resistance.

Scope of delivery

- 1x XF-R 400-1, H-Field Probe 30 MHz up to 6 GHz
- 1x XF-R 3-1, H-Field Probe 30 MHz up to 6 GHz
- 1x XF-B 3-1, H-Field Probe 30 MHz up to 6 GHz
- 1x XF-E 10, E-Field Probe 30 MHz up to 6 GHz
- 1x XF-U 2.5-1, H-Field Probe 30 MHz up to 6 GHz
- 1x SMA-SMA 1 m, SMA-SMA Measuring Cable
- 1x XF 1 qg, XF1 Set Quick Guide
- 1x Case 5, System Case Near-Field Probes

Technical parameters

Frequency range	30 MHz ... 6 GHz
Connector	SMA, male, jack
Weight	400 g
Sizes (L x W x H)	(24 x 19.5 x 6) cm



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Application XF-U 2.5-1



Measurement set-up near-field probes

